

December 2013

FDP7N60NZ / FDPF7N60NZ N-Channel UniFETTM II MOSFET 600 V, 6.5 A, 1.25 Ω

Features

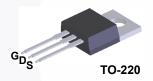
- $R_{DS(on)}$ = 1.05 Ω (Typ.) @ V_{GS} = 10 V, I_D = 3.25 A
- Low Gate Charge (Typ. 13 nC)
- Low C_{rss} (Typ. 7 pF)
- · 100% Avalanche Tested
- · Improved dv/dt Capability
- · ESD Improved Capability
- · RoHS Compliant

Applications

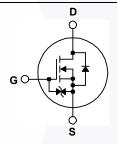
- LCD/ LED/ PDP TV
- Lighting
- Uninterruptible Power Supply
- AC-DC Power Supply

Description

UniFETTM II MOSFET is Fairchild Semiconductor's high voltage MOSFET family based on advanced planar stripe and DMOS technology. This advanced MOSFET family has the smallest on-state resistance among the planar MOSFET, and also provides superior switching performance and higher avalanche energy strength. In addition, internal gate-source ESD diode allows UniFET II MOSFET to withstand over 2kV HBM surge stress. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.







MOSFET Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol		Parameter		FDP7N60NZ	FDPF7N60NZ/ FDPF7N60NZT	Unit	
V_{DSS}	Drain to Source Voltage			6	00	V	
V_{GSS}	Gate to Source Voltage			±	30	V	
	Drain Current	- Continuous (T _C = 25°C)		6.5	6.5*	A	
ID	Dialii Cuiteiit	- Continuous (T _C = 100°C)		3.9	3.9*		
I _{DM}	Drain Current	- Pulsed	(Note 1)	26	26*	Α	
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	275		mJ	
I _{AR}	Avalanche Current		(Note 1)	6.5		Α	
E _{AR}	Repetitive Avalanche Energy	,	(Note 1)	14.7		mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	10		V/ns	
Б	Dower Dissinction	(T _C = 25°C)		147	33	W	
P_D	Power Dissipation	- Derate Above 25°C		1.2	0.26	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150		°С		
T _L	Maximum Lead Temperature	for Soldering, 1/8" from Case fo	r 5 Seconds	3	00	οС	

*Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	FDP7N60NZ	FDPF7N60NZ / FDPF7N60NZT	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.85	3.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	62.5	C/VV

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Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FDP7N60NZ	FDP7N60NZ	TO-220	Tube	N/A	N/A	50 units
FDPF7N60NZ	FDPF7N60NZ	TO-220F	Tube	N/A	N/A	50 units
FDPF7N60NZT	FDPF7N60NZ	TO-220F	Tube	N/A	N/A	50 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	rest Conditions	WIII.	iyp.	wax.	Unit
Off Charac	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_J = 25^{\circ} C$	600	-	-	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C	-	0.6	-	V/°C
1	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V	-	-	1	^
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 480 \text{ V}, T_C = 125^{\circ}\text{C}$	-	-	10	μΑ
I _{GSS}	Gate to Body Leakage Current	V _{GS} = ±25 V, V _{DS} = 0 V	-	-	±10	μΑ
	/					•

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu\text{A}$	3	-	5	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 3.25 \text{ A}$	-	1.05	1.25	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 20 V, I _D = 3.25 A	-	7.3	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V - 25 V V - 0 V	-	550	730	pF
C _{oss}	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	-	70	90	pF
C _{rss}	Reverse Transfer Capacitance	1 10112	-	7	10	pF
Q _{g(tot)}	Total Gate Charge at 10V	V _{DS} = 480 V, I _D = 6.5 A,	-	13	17	nC
Q _{gs}	Gate to Source Gate Charge	V _{GS} = 10 V	-	3	-	nC
Q_{gd}	Gate to Drain "Miller" Charge	(Note 4)	-	5.6	-	nC

Switching Characteristics

	_						
t _{d(on)}	Turn-On Delay Time			-	17.5	45	ns
t _r	Turn-On Rise Time	$V_{DD} = 300 \text{ V}, I_D = 6.5 \text{ A},$		- /	30	70	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V, R_G = 25 Ω		-/	40	90	ns
t _f	Turn-Off Fall Time		(Note 4)	-	25	60	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	6.5	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	26	Α
V_{SD}	Drain to Source Diode Forward Voltage V _{GS} = 0 V, I _{SD} = 6.5 A		-	-	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _{SD} = 6.5 A,	-	250	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	1.4	-	μC

Notes

- 1: Repetitive rating: pulse-width limited by maximum junction temperature.
- 2: L = 13 mH, I_{AS} = 6.5 A, V_{DD} = 50 V, R_{G} = 25 Ω , starting T_{J} = 25°C.
- 3: I $_{SD}~\leq 6.5$ A, di/dt ≤ 200 A/µs, V $_{DD} \leq$ BV $_{DSS}$, starting T $_{J}$ = 25°C.
- 4: Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

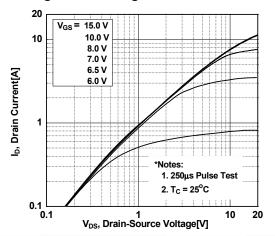


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

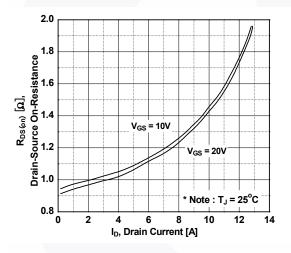


Figure 5. Capacitance Characteristics

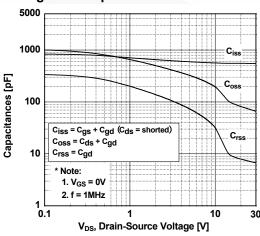


Figure 2. Transfer Characteristics

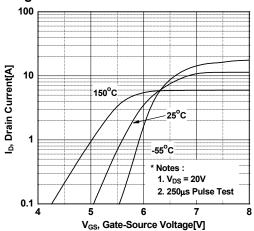


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

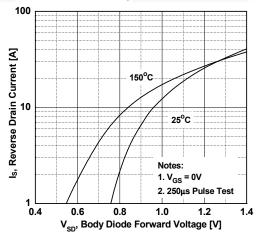
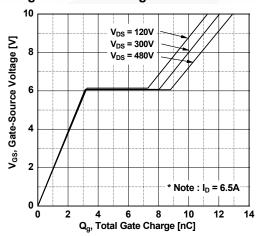


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

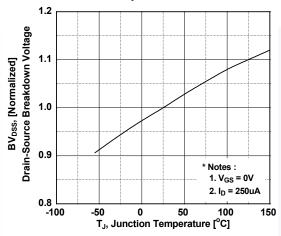


Figure 8. On-Resistance Variation vs Temperature

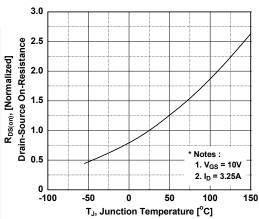


Figure 9. Maximum Safe Operating Area - FDPF7N60NZ/ FDPF7N60NZT

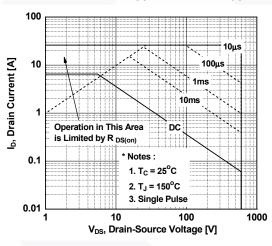


Figure 10. Maximum Safe Operating Area - FDP7N60NZ

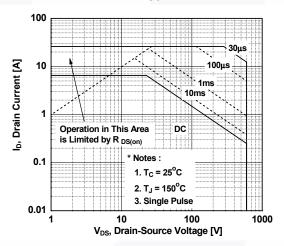
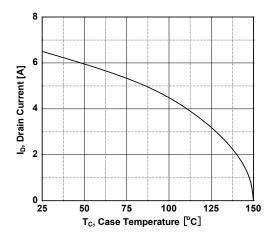


Figure 11. Maximum Drain Current vs. Case Temperature



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Typical Performance Characteristics (Continued)

Figure 12. Transient Thermal Response Curve
- FDPF7N60NZ / FDPF7N60NZT

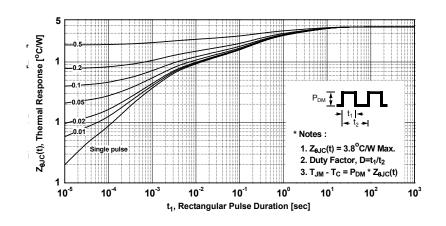
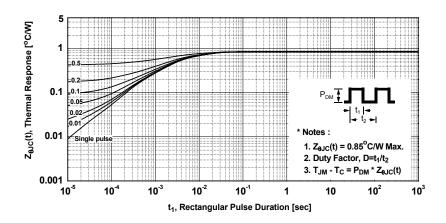


Figure 13. Transient Thermal Response Curve - FDP7N60NZ



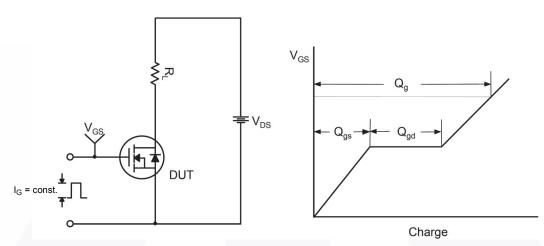


Figure 14. Gate Charge Test Circuit & Waveform

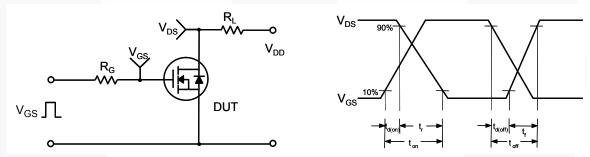


Figure 15. Resistive Switching Test Circuit & Waveforms

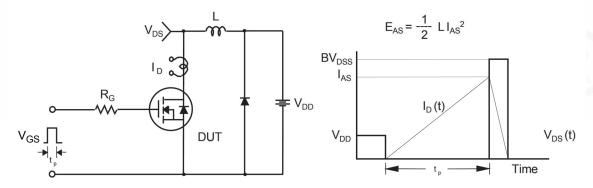


Figure 16. Unclamped Inductive Switching Test Circuit & Waveforms

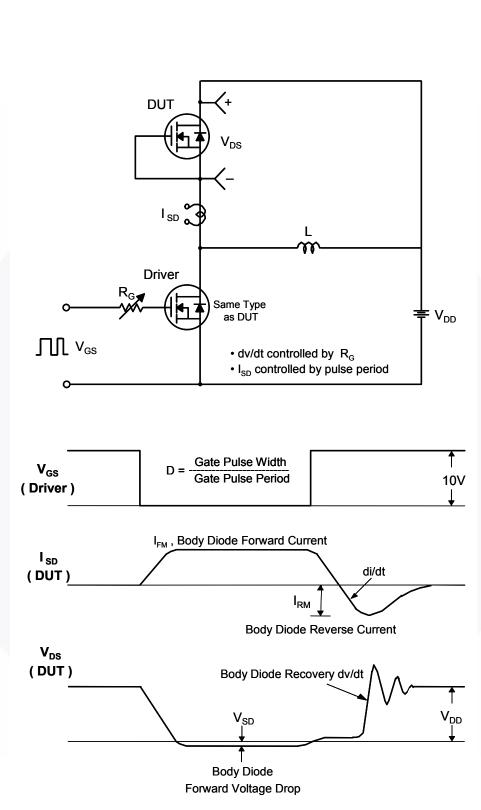
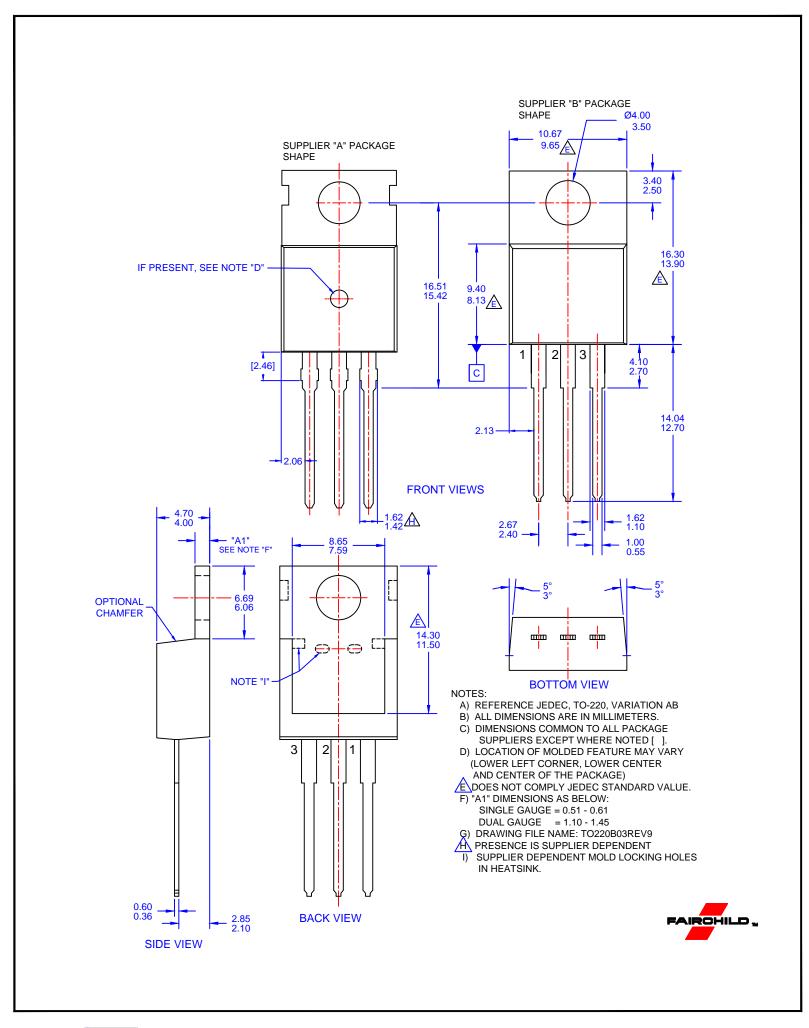
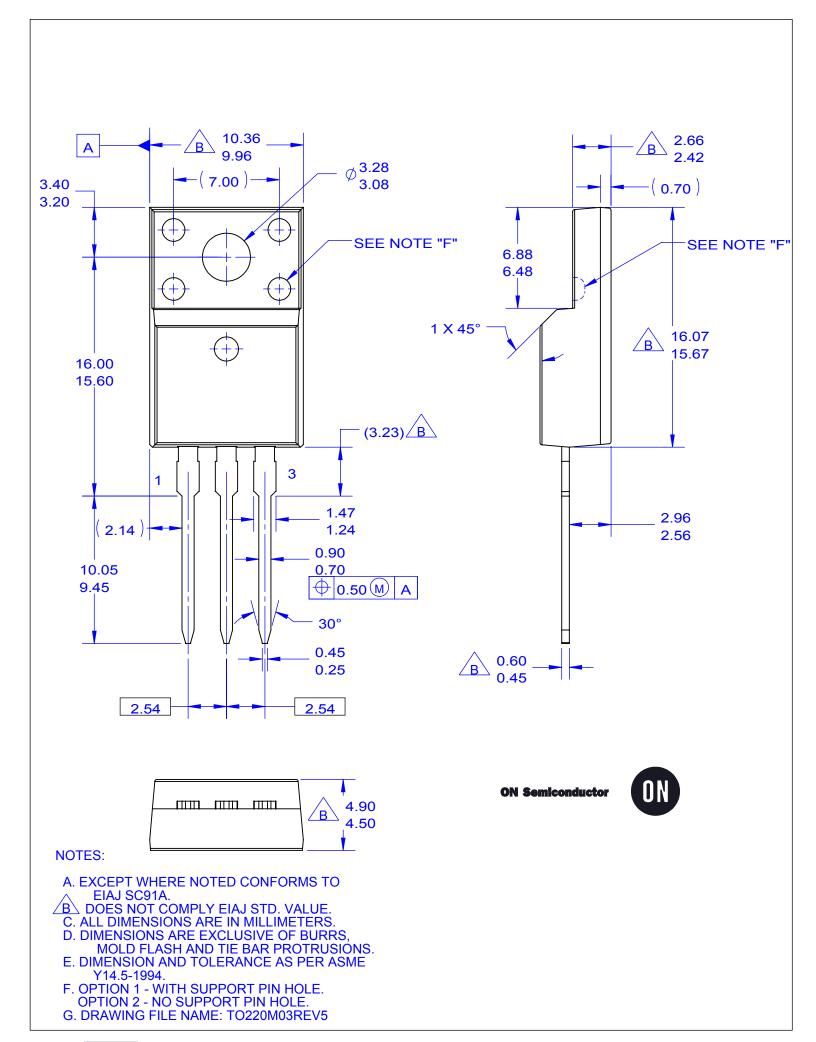


Figure 17. Peak Diode Recovery dv/dt Test Circuit & Waveforms





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